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Application No.	Applicant(s)	
10/643,041	LUH ET AL.	
Examiner	Art Unit	
Dawn Garrett	1774	

	SEARCHED					
Class	Subclass	Date	Examiner			
428	690	2/1/05	QSH			
428	917					
313	504					
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549	472					
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INTERFERENCE SEARCHED					
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		6/1/06	Q4		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
·	DATE	EXMR
STIC structure Dearch	12/20/04	Q¥
EAST search (attached)	2/1/05	ДY
Reviewed Structure Search	8/29/05	Oy
Reviewed Structure search	12/9/05	ØY
Structure search Reviewed probiosonal application	5/25/06	OG .
Reviewed prior Stic seurches	5/25/06	: Og
EAST search (see altached)	6/1/06	Øj

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